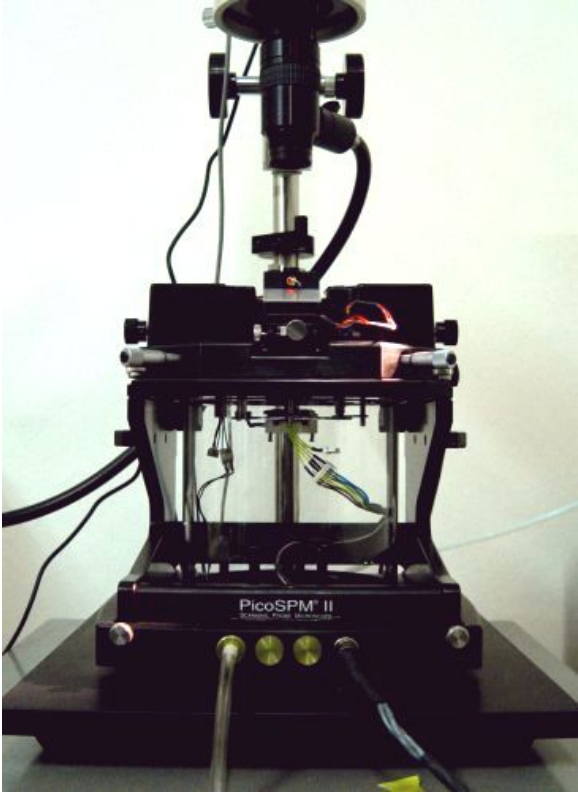


Methods, IMC, Mülhaupt

<p style="text-align: center;">Atomic Force Microscope</p> <p style="text-align: center;"><i>(AFM with MacMode)</i></p>	<p>Model: <i>PicoSPM II</i></p> <p>Unit and Room: <i>ZfN, Albertstraße 23, back building, basement, room nr. 8</i></p> <p>Responsible: <i>Dr. Yi Thomann Dr. Ralf Thomann</i></p> <p>Further information: <i>http://www.fmf.uni-freiburg.de/service/dienstleistungen/mikroskopie/index_htm/</i></p>	
<p>Short Description:</p> <p>Atomic Force Microscope with various imaging modes</p>	<p style="text-align: center;">Picture of the Equipment</p> 	
<p>Available Experiments/Techniques:</p> <p>The AFM allows the morphological and mechanical characterization of small samples with several imaging modes:</p> <ul style="list-style-type: none"> - tapping mode - MacMode - contact mode - phase, amplitude, height mode imaging - hot stage measurements etc. <p>resolution < 1nm</p>		
<p>Special Equipment:</p> <p>Sample preparation equipment</p>		
<p>Measurements on the equipment are currently done by:</p>	<p><input type="checkbox"/> Students</p> <p><input type="checkbox"/> Students after Introduction</p> <p><input checked="" type="checkbox"/> Students after extensive training</p> <p><input checked="" type="checkbox"/> Trained scientific service personal</p>	
<p>Recent Publications, where this instrument was important (optional): Give citation</p>	<p><i>Polymer (2006), 47(11), 3740-3746.</i></p> <p><i>Chinese J. Polym. Sci. 25, 83 (2007)</i></p>	
<p>Typical problems that may be solved with this instrument:</p>	<p><i>The microscope allows the characterization of surfaces of nearly every material, and the investigation of bulk morphologies on microtomed samples. Topography and material properties can be imaged</i></p>	